

RELIABILITY DATA
LTC2400/08/10/12/13/14/15/18/30/31/36/39 LTC2757
6/1/2010

• **OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	154	9845	9927	154.00	0
SSOP/TSSOP	478	0001	0516	355.55	0
	632			509.55	0

• **PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	250	0105	0818	58.85	0
SSOP/TSSOP	2,295	0019	0912	390.79	0
QFN/DFN	230	0847	0849	38.64	0
	2,775			488.28	0

• **TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	200	9850	0321	155.30	0
SSOP/TSSOP	973	0046	0911	480.30	0
	1,173			635.60	0

• **THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	185	9850	0818	97.17	0
SSOP/TSSOP	1,348	0033	0911	368.30	0
QFN/DFN	123	0847	0849	61.50	0
	1,656			526.97	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 23.23 FITS

(3) Mean Time Between Failures in Years = 4,911

Note: 1 FIT = 1 Failure in One Billion Hours.